

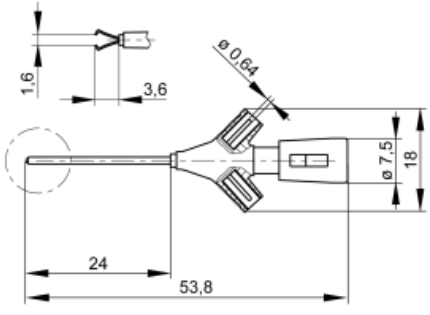


Clamp-type test probe

MICRO-KLEPS



Product	MICRO-KLEPS
description	Miniature clamp-type test probe with rotating grip jaws (SMD technology). The insulated shaft can be bent up to 35°. Suitable for very thin wires and densely packed contact points (1.27 mm IC spacing pitch). Connects with MKL... and MAL...
operating instruction	BA002
article-no. / *colour	9739721xx <div style="display: flex; justify-content: space-around; align-items: center;"> <div style="text-align: center;">  00 black </div> <div style="text-align: center;">  01 red </div> </div>
drawing	
technical data	
connection	2 x unsprung pin Ø 0.64 mm
rated voltage	30 VAC / 60 VDC
measurement cat. acc. to IEC 61010	O ⁽²⁾

0.64 mm system

rated current (consider derating curve)	2 A
material plug	brass, gold plated
housing material	PBT
temperature range acc. To IEC61010 ⁽¹⁾	-25 °C to +70 °C
flammability class acc. to UL 94 (only valid for basic material of housing)	HB
clamp type	rotating grip jaws, tin plated
clamping range	1,6 mm

⁽¹⁾ contact the manufacturer for applications at deviating temperature ranges

⁽²⁾ without rated measurement category, for other circuits that are not directly connected to mains
 stand: 21.06.2022

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